Infineon Technologies - XE169FH200F100LABKXQSA1 Datasheet

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	C166SV2
Core Size	16-Bit
Speed	100MHz
Connectivity	CANbus, EBI/EMI, I²C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I²S, POR, PWM, WDT
Number of I/O	118
Program Memory Size	1.6MB (1.6M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	112K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 30x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	176-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-176-12
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xe169fh200f100labkxqsa1

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Table 5 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
70	P11.4	O0 / I	St/B	**Bit 4 of Port 11, General Purpose Input/Output**
	CCU61_CC62	O1	St/B	**CCU61 Channel 2 Output**
	U3C1_DOUT	O2	St/B	**USIC3 Channel 1 Shift Data Output**
	RxDC5B	I	St/B	**CAN Node 5 Receive Data Input**
	CCU61_CC62INB	I	St/B	**CCU61 Channel 2 Input**
	U3C1_DX0B	I	St/B	**USIC3 Channel 1 Shift Data Input**
71	P12.10	O0 / I	St/B	**Bit 10 of Port 12, General Purpose Input/Output**
	CC2_CC16	O1	St/B	**CAPCOM2 Channel 16 Compare Output**
	CCU63_COUT62	O2	St/B	**CCU63 Channel 2 Output**
	U4C0_DX1C	I	St/B	**USIC4 Channel 0 Shift Clock Input**
	U3C1_DX1C	I	St/B	**USIC3 Channel 1 Shift Clock Input**
72	P2.2	O0 / I	St/B	**Bit 2 of Port 2, General Purpose Input/Output**
	TxDC1	O1	St/B	**CAN Node 1 Transmit Data Output**
	CCU63_CC62	O2	St/B	**CCU63 Channel 2 Output**
	AD15	OH / IH	St/B	**External Bus Interface Address/Data Line 15**
	CCU63_CC62INB	I	St/B	**CCU63 Channel 2 Input**
	ESR2_5	I	St/B	**ESR2 Trigger Input 5**
73	P11.3	O0 / I	St/B	**Bit 3 of Port 11, General Purpose Input/Output**
	CCU61_COUT63	O1	St/B	**CCU61 Channel 3 Output**
	CCU61_COUT62	O2	St/B	**CCU61 Channel 2 Output**
	TxDC5	O3	St/B	**CAN Node 5 Transmit Data Input**
	CCU61_T13HRF	I	St/B	**External Run Control Input for T13 of CCU61**
	U4C0_DX1A	I	St/B	**USIC4 Channel 0 Shift Clock Input**

Table 5 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
123	P10.5	O0 / I	St/B	**Bit 5 of Port 10, General Purpose Input/Output**
	U0C1_SCLKOUT	O1	St/B	**USIC0 Channel 1 Shift Clock Output**
	CCU60_COUT62	O2	St/B	**CCU60 Channel 2 Output**
	U2C0_DOUT	O3	St/B	**USIC2 Channel 0 Shift Data Output**
	AD5	OH / IH	St/B	**External Bus Interface Address/Data Line 5**
	U0C1_DX1B	I	St/B	**USIC0 Channel 1 Shift Clock Input**
124	P3.5	O0 / I	St/B	**Bit 5 of Port 3, General Purpose Input/Output**
	U2C1_SCLKOUT	O1	St/B	**USIC2 Channel 1 Shift Clock Output**
	U2C0_SELO2	O2	St/B	**USIC2 Channel 0 Select/Control 2 Output**
	U0C0_SELO5	O3	St/B	**USIC0 Channel 0 Select/Control 5 Output**
	U2C1_DX1A	I	St/B	**USIC2 Channel 1 Shift Clock Input**
125	P0.6	O0 / I	St/B	**Bit 6 of Port 0, General Purpose Input/Output**
	U1C1_DOUT	O1	St/B	**USIC1 Channel 1 Shift Data Output**
	TxDC1	O2	St/B	**CAN Node 1 Transmit Data Output**
	CCU61_COUT63	O3	St/B	**CCU61 Channel 3 Output**
	A6	OH	St/B	**External Bus Interface Address Line 6**
	U1C1_DX0A	I	St/B	**USIC1 Channel 1 Shift Data Input**
	CCU61_CTRAPA	I	St/B	**CCU61 Emergency Trap Input**
	U1C1_DX1B	I	St/B	**USIC1 Channel 1 Shift Clock Input**

Table 5 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
129	P10.7	O0 / I	St/B	**Bit 7 of Port 10, General Purpose Input/Output**
	U0C1_DOUT	O1	St/B	**USIC0 Channel 1 Shift Data Output**
	CCU60_COUT63	O2	St/B	**CCU60 Channel 3 Output**
	AD7	OH / IH	St/B	**External Bus Interface Address/Data Line 7**
	U0C1_DX0B	I	St/B	**USIC0 Channel 1 Shift Data Input**
	CCU60_CCPOS0A	I	St/B	**CCU60 Position Input 0**
	RxDC4C	I	St/B	**CAN Node 4 Receive Data Input**
	T4INB	I	St/B	**GPT12E Timer T4 Count/Gate Input**
130	P0.7	O0 / I	St/B	**Bit 7 of Port 0, General Purpose Input/Output**
	U1C1_DOUT	O1	St/B	**USIC1 Channel 1 Shift Data Output**
	U1C0_SELO3	O2	St/B	**USIC1 Channel 0 Select/Control 3 Output**
	TxDC3	O3	St/B	**CAN Node 3 Transmit Data Output**
	A7	OH	St/B	**External Bus Interface Address Line 7**
	U1C1_DX0B	I	St/B	**USIC1 Channel 1 Shift Data Input**
	CCU61_CTRAPB	I	St/B	**CCU61 Emergency Trap Input**
131	P3.7	O0 / I	St/B	**Bit 7 of Port 3, General Purpose Input/Output**
	U2C1_DOUT	O1	St/B	**USIC2 Channel 1 Shift Data Output**
	U2C0_SELO3	O2	St/B	**USIC2 Channel 0 Select/Control 3 Output**
	U0C0_SELO7	O3	St/B	**USIC0 Channel 0 Select/Control 7 Output**
	U2C1_DX0B	I	St/B	**USIC2 Channel 1 Shift Data Input**

Table 5 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
151	P1.3	O0 / I	St/B	**Bit 3 of Port 1, General Purpose Input/Output**
	CCU62_COUT63	O1	St/B	**CCU62 Channel 3 Output**
	U1C0_SELO7	O2	St/B	**USIC1 Channel 0 Select/Control 7 Output**
	U2C0_SELO4	O3	St/B	**USIC2 Channel 0 Select/Control 4 Output**
	A11	OH	St/B	**External Bus Interface Address Line 11**
	ESR2_4	I	St/B	**ESR2 Trigger Input 4**
	CCU62_T12HRB	I	St/B	**External Run Control Input for T12 of CCU62**
152	P13.3	O0 / I	St/B	**Bit 3 of Port 13, General Purpose Input/Output**
	CC1_CC11	O1 / I	St/B	**CAPCOM1 CC11IO Capture Inp./ Compare Out.**
	CCU60_CC60	O2	St/B	**CCU60 Channel 0 Output**
	U4C1_SCLKOUT	O3	St/B	**USIC4 Channel 1 Shift Clock Output**
	TMS_E	IH	St/B	**JTAG Test Mode Selection Input**
	CCU60_CC60INC	I	St/B	**CCU60 Channel 0 Input**
153	P9.4	O0 / I	St/B	**Bit 4 of Port 9, General Purpose Input/Output**
	CCU63_COUT61	O1	St/B	**CCU63 Channel 1 Output**
	U2C0_DOUT	O2	St/B	**USIC2 Channel 0 Shift Data Output**
	CCU62_COUT63	O3	St/B	**CCU62 Channel 3 Output**

Table 5 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
162	P13.5	O0 / I	St/B	**Bit 5 of Port 13, General Purpose Input/Output**
	CC1_CC13	O1 / I	St/B	**CAPCOM1 CC13IO Capture Inp./ Compare Out.**
	CCU60_COUT62	O2	St/B	**CCU60 Channel 2 Output**
	U3C0_MCLKOUT	O3	St/B	**USIC3 Channel 0 Master Clock Output**
	U4C1_DX0B	I	St/B	**USIC4 Channel 1 Shift Data Input**
	TDI_E	IH	St/B	**JTAG Test Data Input**
163	P1.6	O0 / I	St/B	**Bit 6 of Port 1, General Purpose Input/Output**
	CCU62_CC61	O1 / I	St/B	**CCU62 Channel 1 Output**
	U1C1_SELO2	O2	St/B	**USIC1 Channel 1 Select/Control 2 Output**
	U2C0_DOUT	O3	St/B	**USIC2 Channel 0 Shift Data Output**
	A14	OH	St/B	**External Bus Interface Address Line 14**
	U2C0_DX0D	I	St/B	**USIC2 Channel 0 Shift Data Input**
	CCU62_CC61INA	I	St/B	**CCU62 Channel 1 Input**
	U4C1_DX0A	I	St/B	**USIC4 Channel 1 Shift Data Input**
164	P9.7	O0 / I	St/B	**Bit 7 of Port 9, General Purpose Input/Output**
	CCU62_COUT60	O1	St/B	**CCU62 Channel 0 Output**
	CCU62_COUT63	O2	St/B	**CCU62 Channel 3 Output**
	CCU63_CTRAPB	I	St/B	**CCU63 Emergency Trap Input**
	U2C0_DX1D	I	St/B	**USIC2 Channel 0 Shift Clock Input**
	CCU60_CCPOS0B	I	St/B	**CCU60 Position Input 0**

3.14 MultiCAN Module

The MultiCAN module contains independently operating CAN nodes with Full-CAN functionality which are able to exchange Data and Remote Frames using a gateway function. Transmission and reception of CAN frames is handled in accordance with CAN specification V2.0 B (active). Each CAN node can receive and transmit standard frames with 11-bit identifiers as well as extended frames with 29-bit identifiers.

All CAN nodes share a common set of message objects. Each message object can be individually allocated to one of the CAN nodes. Besides serving as a storage container for incoming and outgoing frames, message objects can be combined to build gateways between the CAN nodes or to set up a FIFO buffer.

Note: The number of CAN nodes and message objects depends on the selected device type.

The message objects are organized in double-chained linked lists, where each CAN node has its own list of message objects. A CAN node stores frames only into message objects that are allocated to its own message object list and it transmits only messages belonging to this message object list. A powerful, command-driven list controller performs all message object list operations.

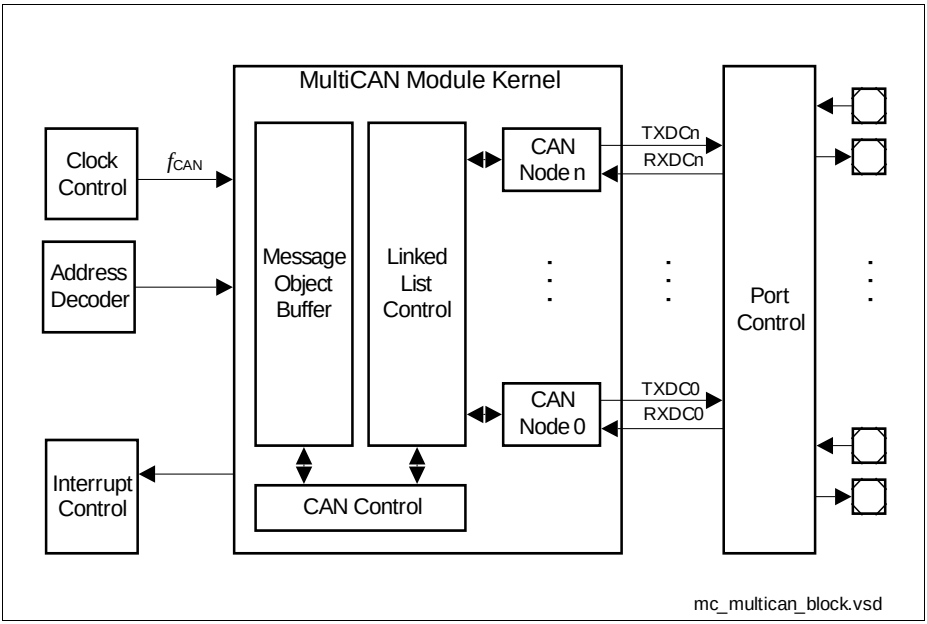

Figure 12 Block Diagram of MultiCAN Module

4 Electrical Parameters

The operating range for the XE169xH is defined by its electrical parameters. For proper operation the specified limits must be respected when integrating the device in its target environment.

4.1 General Parameters

These parameters are valid for all subsequent descriptions, unless otherwise noted.

Table 11 Absolute Maximum Rating Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Output current on a pin when high value is driven	I_{OH} SR	-30	–	–	mA	
Output current on a pin when low value is driven	I_{OL} SR	–	–	30	mA	
Overload current	I_{OV} SR	-10	–	10	mA	1)
Absolute sum of overload currents	$\Sigma\|I_{OV}\|$ SR	–	–	100	mA	1)
Junction Temperature	T_J SR	-40	–	150	°C	
Storage Temperature	T_{ST} SR	-65	–	150	°C	
Digital supply voltage for IO pads and voltage regulators	V_{DDP} SR	-0.5	–	6.0	V	
Voltage on any pin with respect to ground (Vss)	V_{IN} SR	-0.5	–	V_{DDP} + 0.5	V	$V_{IN} \leq V_{DDP(max)}$

1) Overload condition occurs if the input voltage V_{IN} is out of the absolute maximum rating range. In this case the current must be limited to the listed values by design measures.

Note: Stresses above the values listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only. Functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for an extended time may affect device reliability.
During absolute maximum rating overload conditions ($V_{IN} > V_{DDP}$ or $V_{IN} < V_{SS}$) the voltage on V_{DDP} pins with respect to ground (V_{SS}) must not exceed the values defined by the absolute maximum ratings.

Table 12 Operating Conditions (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Overload current coupling factor for digital I/O pins	K_{OVD} CC	–	1.0 x 10^{-2}	3.0 x 10^{-2}		I_{OV}< 0 mA; not subject to production test
		–	1.0 x 10^{-4}	5.0 x 10^{-3}		I_{OV}> 0 mA; not subject to production test
Absolute sum of overload currents	$\Sigma\|I_{OV}\|$ SR	–	–	50	mA	not subject to production test
Digital core supply voltage for domain M[8)]	V_{DDIM} CC	–	1.5	–		
Digital core supply voltage for domain 1[8)]	V_{DDI1} CC	–	1.5	–		
Digital supply voltage for IO pads and voltage regulators	V_{DDP} SR	3.0	–	5.5	V	
Digital ground voltage	V_{SS} SR	–	0	–	V	

1) To ensure the stability of the voltage regulators the EVRs must be buffered with ceramic capacitors. Separate buffer capacitors with the recomended values shall be connected as close as possible to each V_{DDIM} and V_{DDI1} pin to keep the resistance of the board tracks below 2 Ohm. Connect all V_{DDI1} pins together. The minimum capacitance value is required for proper operation under all conditions (e.g. temperature). Higher values slightly increase the startup time.

2) Use one Capacitor for each pin.

3) This is the reference load. For bigger capacitive loads, use the derating factors listed in the PAD properties section.

4) The timing is valid for pin drivers operating in default current mode (selected after reset). Reducing the output current may lead to increased delays or reduced driving capability (C_L).

5) The operating frequency range may be reduced for specific device types. This is indicated in the device designation (...FxxL). 80 MHz devices are marked ...F80L.

6) Overload conditions occur if the standard operating conditions are exceeded, i.e. the voltage on any pin exceeds the specified range: $V_{OV} > V_{IHmax}$ ($I_{OV} > 0$) or $V_{OV} < V_{ILmin}$ (($I_{OV} < 0$). The absolute sum of input overload currents on all pins may not exceed 50 mA. The supply voltages must remain within the specified limits. Proper operation under overload conditions depends on the application. Overload conditions must not occur on pin XTAL1 (powered by V_{DDIM}).

4.3.1 DC Parameters for Upper Voltage Area

Keeping signal levels within the limits specified in this table ensures operation without overload conditions. For signal levels outside these specifications, also refer to the specification of the overload current I_{OV}.

Note: Operating Conditions apply.

Table 15 is valid under the following conditions: V_{DDP}typ. 5 V; $V_{DDP}\geq$ 4.5 V; $V_{DDP}\leq$ 5.5 V

Table 15 DC Characteristics for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Pin capacitance (digital inputs/outputs). To be doubled for double bond pins.[1)]	C_{IO} CC	–	–	10	pF	not subject to production test
Input Hysteresis[2)]	HYS CC	0.11 x V_{DDP}	–	–	V	R_S= 0 Ohm
Absolute input leakage current on pins of analog ports[3)]	$\|I_{OZ1}\|$ CC	–	10	200	nA	$V_{IN}> V_{SS}$ V; $V_{IN}< V_{DDP}$
Absolute input leakage current for all other pins. To be doubled for double bond pins.[3)1)4)]	$\|I_{OZ2}\|$ CC	–	0.2	5	µA	$T_J\leq$ 110 °C; $V_{IN}> V_{SS}$ V; $V_{IN}< V_{DDP}$
		–	0.2	15	µA	$T_J\leq$ 150 °C; $V_{IN}> V_{SS}$ V; $V_{IN}< V_{DDP}$
Pull Level Force Current[5)]	$\|I_{PLF}\|$ SR	250	–	–	µA	$V_{IN}\geq V_{IHmin}$*(pulldown_enabled)* ; $V_{IN}\leq V_{ILmax}$*(pull up_enabled)*
Pull Level Keep Current[6)]	$\|I_{PLK}\|$ SR	–	–	30	µA	$V_{IN}\geq V_{IHmin}$*(pull up_enabled)* ; $V_{IN}\leq V_{ILmax}$*(pull down_enabled)*
Input high voltage (all except XTAL1)	V_{IH} SR	0.7 x V_{DDP}	–	V_{DDP} + 0.3	V	
Input low voltage (all except XTAL1)	V_{IL} SR	-0.3	–	0.3 x V_{DDP}	V	

4.3.3 Power Consumption

The power consumed by the XE169xH depends on several factors such as supply voltage, operating frequency, active circuits, and operating temperature. The power consumption specified here consists of two components:

- The switching current I_S depends on the device activity
- The leakage current I_{LK} depends on the device temperature

To determine the actual power consumption, always both components, switching current I_S and leakage current I_{LK} must be added:

$I_{DDP} = I_S + I_{LK}$.

Note: The power consumption values are not subject to production test. They are verified by design/characterization.
To determine the total power consumption for dimensioning the external power supply, also the pad driver currents must be considered.

The given power consumption parameters and their values refer to specific operating conditions:

- **Active mode**:
  Regular operation, i.e. peripherals are active, code execution out of Flash.
- **Stopover mode**:
  Crystal oscillator and PLL stopped, Flash switched off, clock in domain DMP_1 stopped.

Note: The maximum values cover the complete specified operating range of all manufactured devices.
The typical values refer to average devices under typical conditions, such as nominal supply voltage, room temperature, application-oriented activity.
After a power reset, the decoupling capacitors for V_{DDIM} and V_{DDI1} are charged with the maximum possible current.

For additional information, please refer to **Section 5.2**, **Thermal Considerations**.

Note: Operating Conditions apply.

4.5 System Parameters

The following parameters specify several aspects which are important when integrating the XE169xH into an application system.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply.

Table 21 Various System Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Short-term deviation of internal clock source frequency[1]	Δf_{INT} CC	-1	–	1	%	$\Delta T_J \leq 10°C$
Internal clock source frequency	f_{INT} CC	4.8	5.0	5.2	MHz	
Wakeup clock source frequency[2]	f_{WU} CC	400	–	700	kHz	FREQSEL= 00
		210	–	390	kHz	FREQSEL= 01
		140	–	260	kHz	FREQSEL= 10
		110	–	200	kHz	FREQSEL= 11
Startup time from power-on with code execution from Flash	t_{SPO} CC	1.9	2.6	3.2	ms	f_{WU}= 500 kHz
Startup time from stopover mode with code execution from PSRAM	t_{SSO} CC	11 / f_{WU}[3]	–	12 / f_{WU}[3]	µs	
Core voltage (PVC) supervision level	V_{PVC} CC	V_{LV} - 0.03	V_{LV}	V_{LV} + 0.07[4]	V	[5]
Supply watchdog (SWD) supervision level	V_{SWD} CC	V_{LV} - 0.10[6]	V_{LV}	V_{LV} + 0.15	V	voltage_range= lower [5]
		V_{LV} - 0.15	V_{LV}	V_{LV} + 0.15	V	voltage_range= upper [5]

1) The short-term frequency deviation refers to a timeframe of a few hours and is measured relative to the current frequency at the beginning of the respective timeframe. This parameter is useful to determine a time span for re-triggering a LIN synchronization.

2) This parameter is tested for the fastest and the slowest selection. The medium selections are not subject to production test - verified by design/characterization

3) f_{WU} in MHz

Table 24 Flash Parameters (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Number of erase cycles	N_{ER} SR	–	–	15.000	cycles	$t_{RET} \geq$ 5 years; Valid for up to 64 user selected sectors (data storage)
		–	–	1.000	cycles	$t_{RET} \geq$ 20 years

1) All Flash module(s) can be erased/programmed while code is executed and/or data is read from only one Flash module or from PSRAM. The Flash module that delivers code/data can, of course, not be erased/programmed.
2) Flash module 6 can be erased/programmed while code is executed and/or data is read from any other Flash module.
3) Value of IMB_IMBCTRL.WSFLASH.
4) Value of IMB_IMBCTRL.WSFLE.
5) Programming and erase times depend on the internal Flash clock source. The control state machine needs a few system clock cycles. This increases the stated durations noticably only at extremely low system clock frequencies.

Access to the XE169xH Flash modules is controlled by the IMB. Built-in prefetch mechanisms optimize the performance for sequential access.

Flash access waitstates only affect non-sequential access. Due to prefetch mechanisms, the performance for sequential access (depending on the software structure) is only partially influenced by waitstates.

4.7.2 Definition of Internal Timing

The internal operation of the XE169xH is controlled by the internal system clock f_{SYS}.

Because the system clock signal f_{SYS} can be generated from a number of internal and external sources using different mechanisms, the duration of the system clock periods (TCSs) and their variation (as well as the derived external timing) depend on the mechanism used to generate f_{SYS}. This must be considered when calculating the timing for the XE169xH.

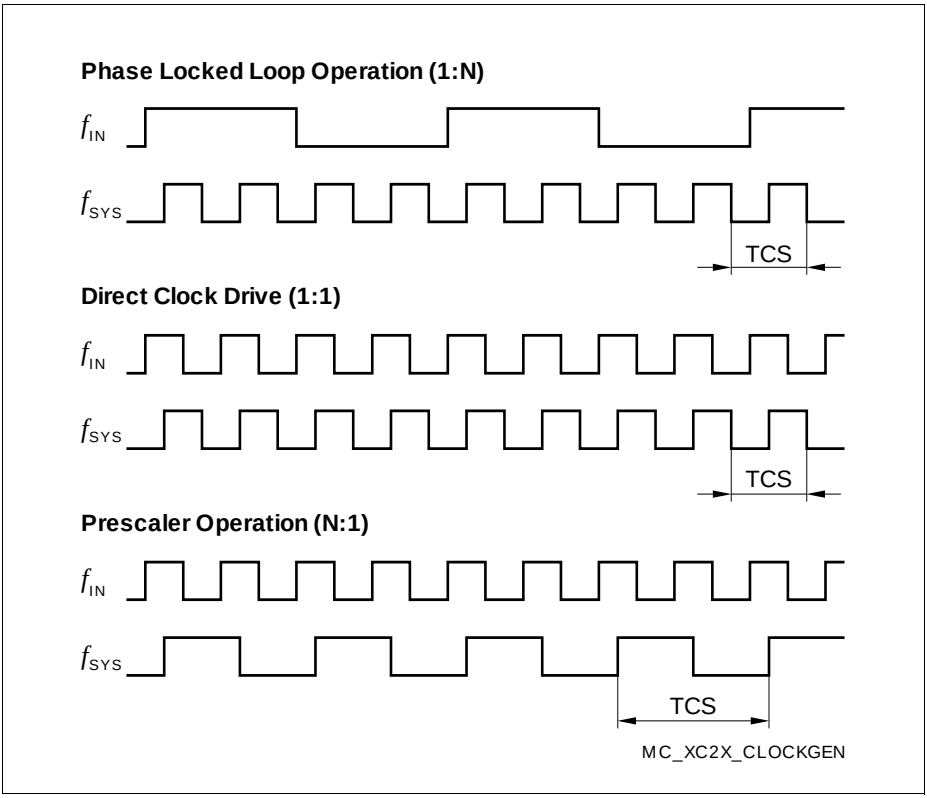

Figure 19 Generation Mechanisms for the System Clock

*Note: The example of PLL operation shown in **Figure 19** uses a PLL factor of 1:4; the example of prescaler operation uses a divider factor of 2:1.*

The specification of the external timing (AC Characteristics) depends on the period of the system clock (TCS).

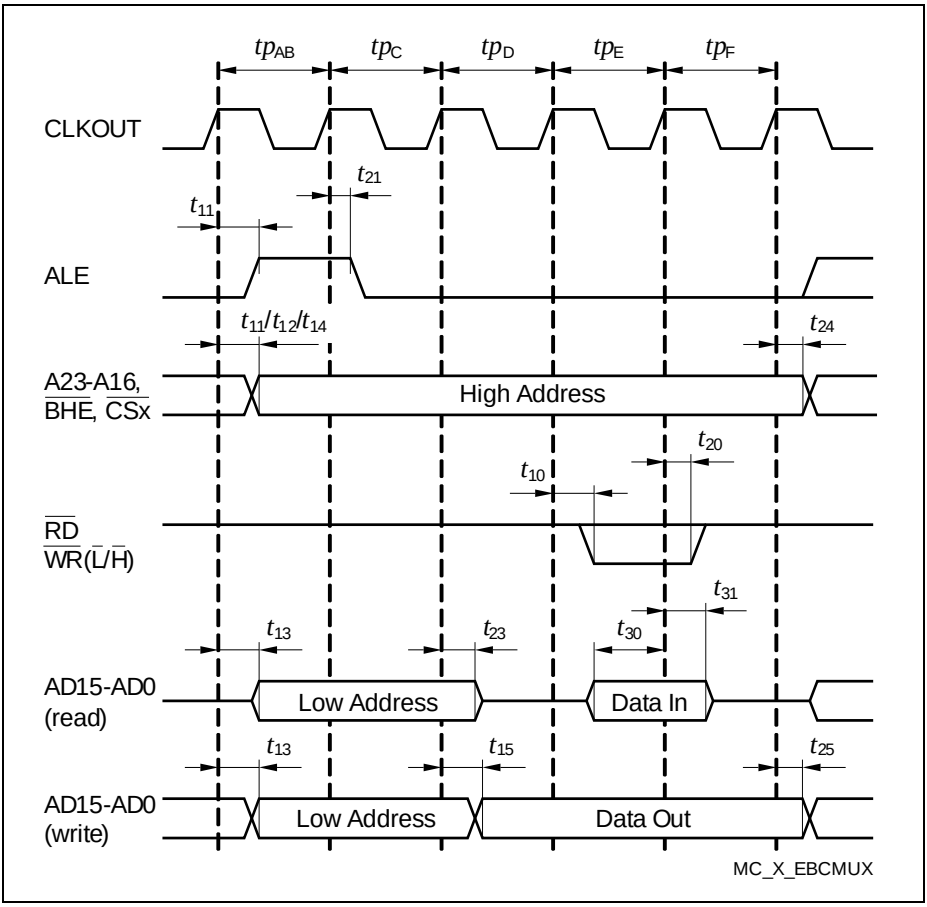

Figure 23 Multiplexed Bus Cycle

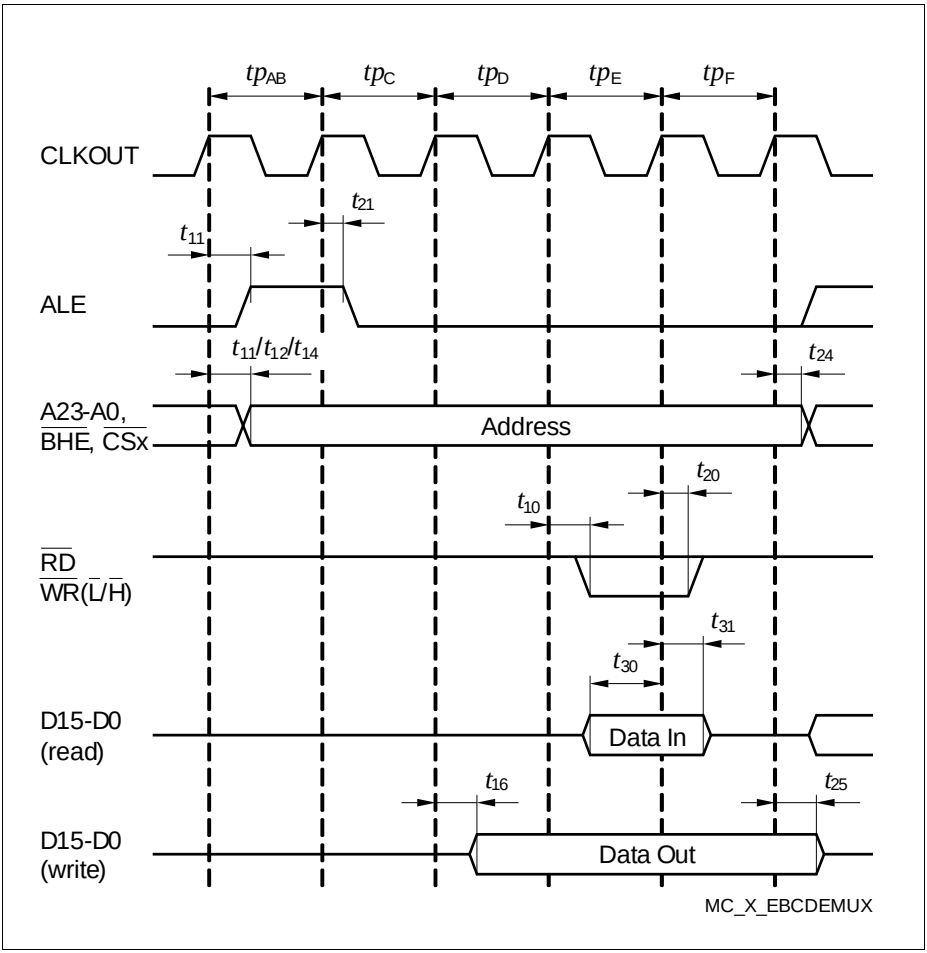

Figure 24 Demultiplexed Bus Cycle

4.7.5.1 Bus Cycle Control with the READY Input

The duration of an external bus cycle can be controlled by the external circuit using the READY input signal. The polarity of this input signal can be selected.

Synchronous READY permits the shortest possible bus cycle but requires the input signal to be synchronous to the reference signal CLKOUT.

An asynchronous READY signal puts no timing constraints on the input signal but incurs a minimum of one waitstate due to the additional synchronization stage. The minimum

duration of an asynchronous READY signal for safe synchronization is one CLKOUT period plus the input setup time.

An active READY signal can be deactivated in response to the trailing (rising) edge of the corresponding command ($\overline{RD}$ or $\overline{WR}$).

If the next bus cycle is controlled by READY, an active READY signal must be disabled before the first valid sample point in the next bus cycle. This sample point depends on the programmed phases of the next cycle.

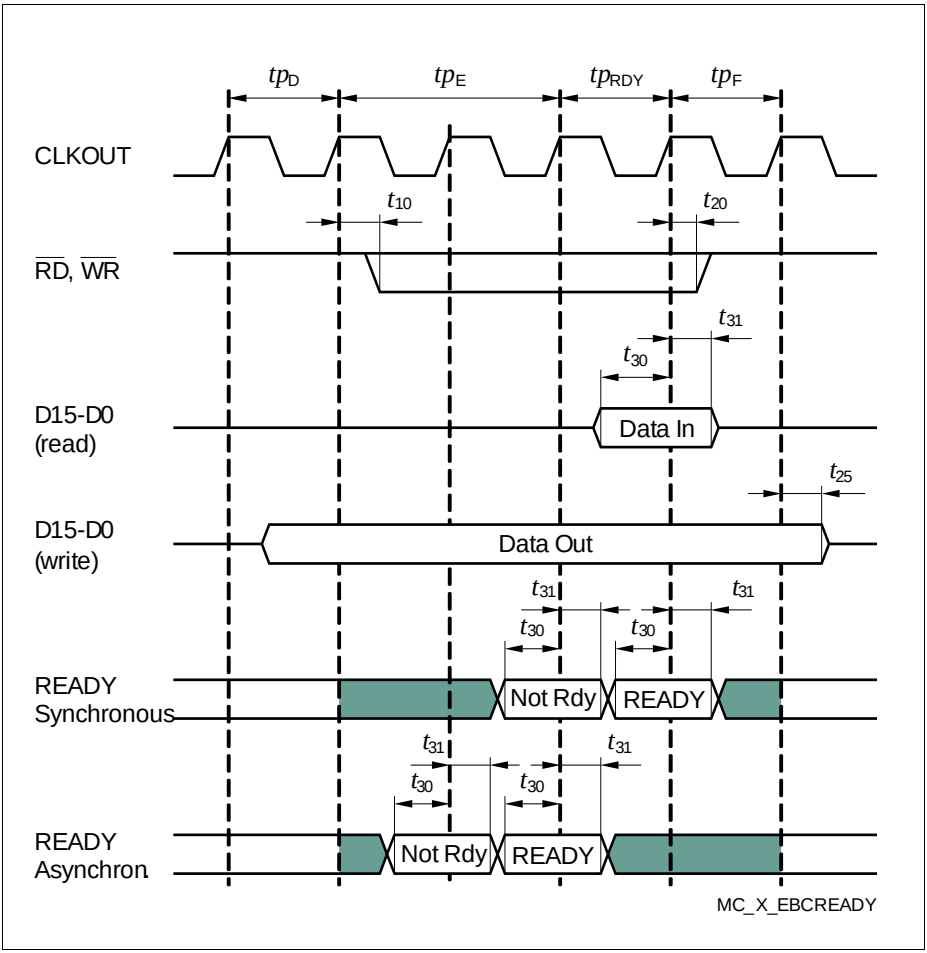

Figure 25 READY Timing

Note: If the READY input is sampled inactive at the indicated sampling point (“Not Rdy”) a READY-controlled waitstate is inserted (tpRDY),
sampling the READY input active at the indicated sampling point (“Ready”) terminates the currently running bus cycle.
Note the different sampling points for synchronous and asynchronous READY.
This example uses one mandatory waitstate (see tpE) before the READY input value is used.

Table 39 JTAG Interface Timing for Upper Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
TCK low time	t_3 SR	16	–	–	ns	
TCK clock rise time	t_4 SR	–	–	8	ns	
TCK clock fall time	t_5 SR	–	–	8	ns	
TDI/TMS setup to TCK rising edge	t_6 SR	6	–	–	ns	
TDI/TMS hold after TCK rising edge	t_7 SR	6	–	–	ns	
TDO valid from TCK falling edge (propagation delay)[2]	t_8 CC	–	25	29	ns	
TDO high impedance to valid output from TCK falling edge[3][2]	t_9 CC	–	25	29	ns	
TDO valid output to high impedance from TCK falling edge[2]	t_{10} CC	–	25	29	ns	
TDO hold after TCK falling edge[2]	t_{18} CC	5	–	–	ns	

1) Under typical conditions, the JTAG interface can operate at transfer rates up to 20 MHz.
2) The falling edge on TCK is used to generate the TDO timing.
3) The setup time for TDO is given implicitly by the TCK cycle time.

Table 40 is valid under the following conditions: C_L= 20 pF; voltage_range= lower

Table 40 JTAG Interface Timing for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
TCK clock period	t_1 SR	50	–	–	ns	
TCK high time	t_2 SR	16	–	–	ns	
TCK low time	t_3 SR	16	–	–	ns	
TCK clock rise time	t_4 SR	–	–	8	ns	
TCK clock fall time	t_5 SR	–	–	8	ns	
TDI/TMS setup to TCK rising edge	t_6 SR	6	–	–	ns	

If different device types are considered or planned for an application, it must be ensured that the board layout fits all packages under consideration.

Package Outlines

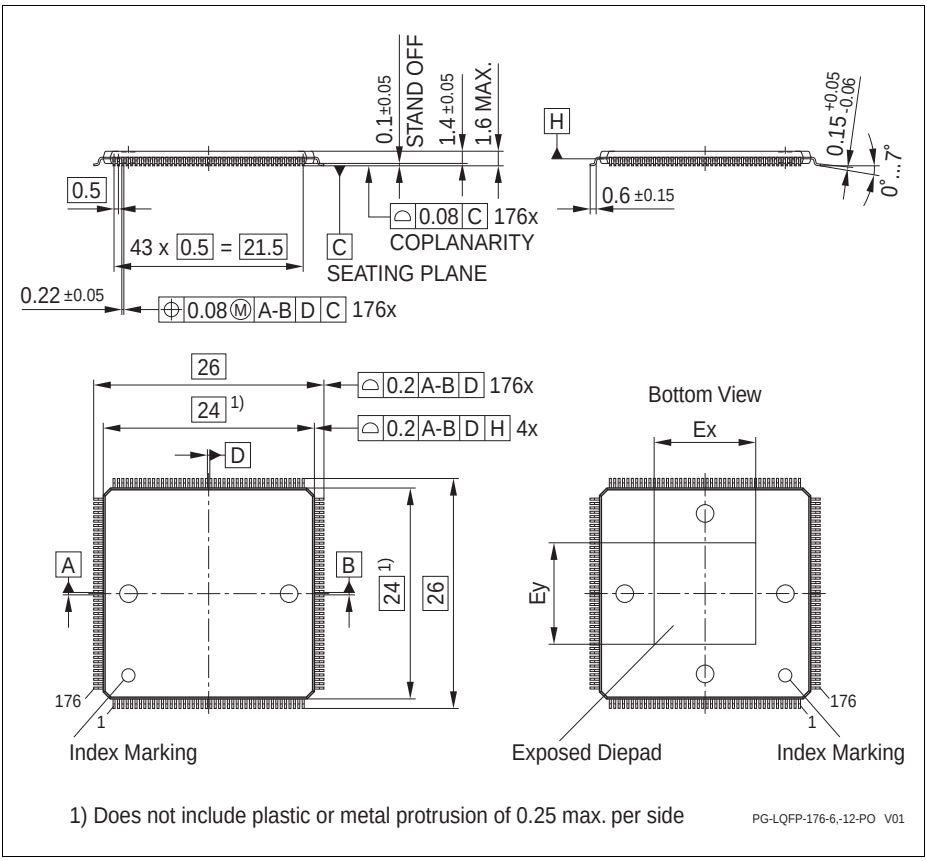

Figure 32 PG-LQFP-176-12 (Plastic Green Thin Quad Flat Package)

All dimensions in mm.

You can find complete information about Infineon packages, packing and marking in our Infineon Internet Page “Packages”: **http://www.infineon.com/packages**